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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	72MHz
Connectivity	CANbus, I²C, IrDA, LINbus, SPI, UART/USART, USB OTG
Peripherals	DMA, POR, PWM, Voltage Detect, WDT
Number of I/O	80
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	64K x 8
Voltage - Supply (Vcc/Vdd)	2V ~ 3.6V
Data Converters	A/D 16x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f105vct7

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2.2 Full compatibility throughout the family

The STM32F105xx and STM32F107xx constitute the connectivity line family whose members are fully pin-to-pin, software and feature compatible.

The STM32F105xx and STM32F107xx are a drop-in replacement for the low-density (STM32F103x4/6), medium-density (STM32F103x8/B) and high-density (STM32F103xC/D/E) performance line devices, allowing the user to try different memory densities and peripherals providing a greater degree of freedom during the development cycle.

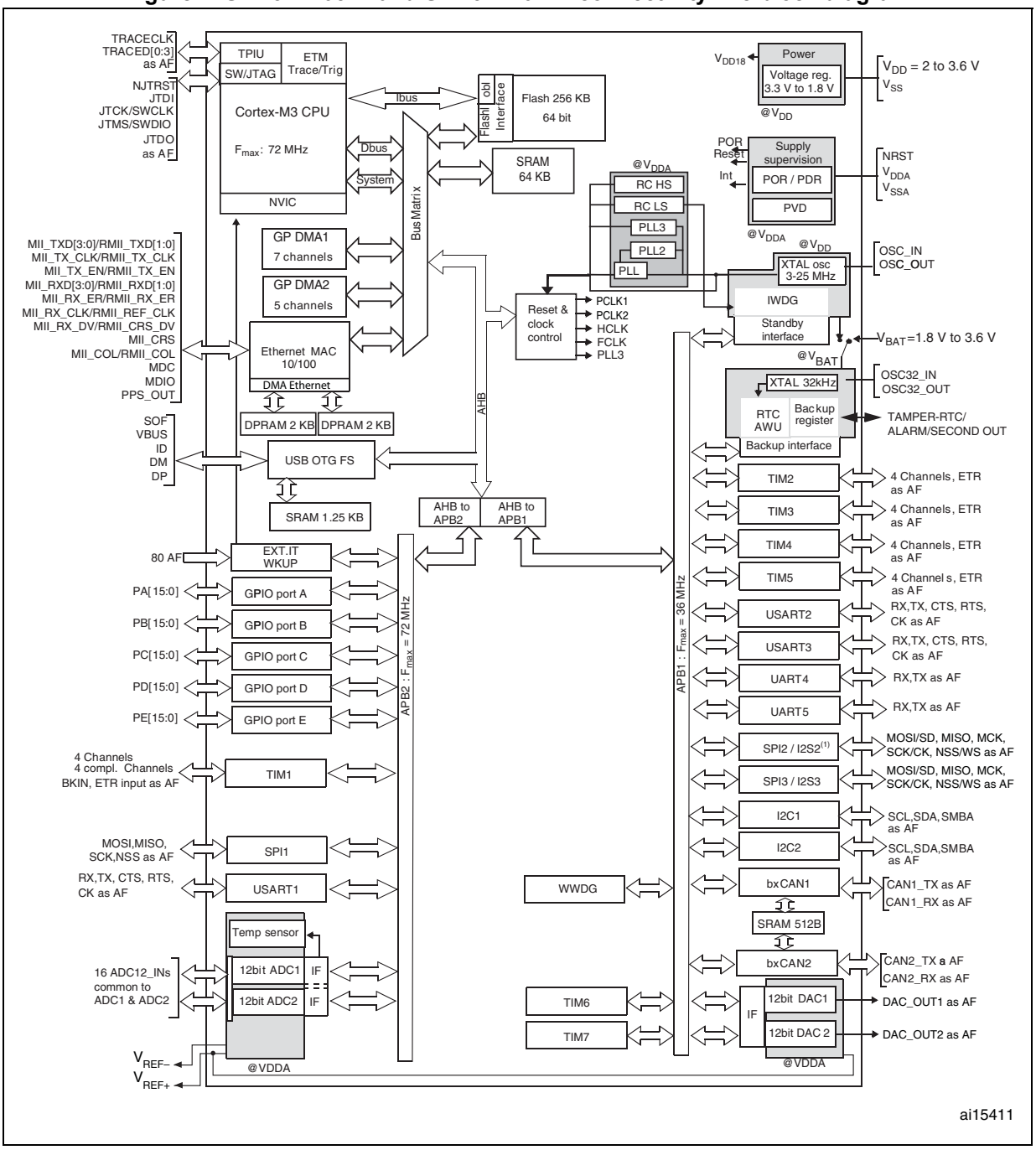
Table 3. STM32F105xx and STM32F107xx family versus STM32F103xx family(1)

<table>
<tr><th>STM32 device</th><th colspan="2">Low-density STM32F103xx devices</th><th colspan="3">Medium-density STM32F103xx devices</th><th colspan="3">High-density STM32F103xx devices</th><th colspan="3">STM32F105xx</th><th colspan="2">STM32F107xx</th></tr>
<tr><td>Flash size (KB)</td><td>16</td><td>32</td><td>32</td><td>64</td><td>128</td><td>256</td><td>384</td><td>512</td><td>64</td><td>128</td><td>256</td><td>128</td><td>256</td></tr>
<tr><td>RAM size (KB)</td><td>6</td><td>10</td><td>10</td><td>20</td><td>20</td><td>48</td><td>64</td><td>64</td><td>64</td><td>64</td><td>64</td><td>64</td><td>64</td></tr>
<tr><td>144 pins</td><td colspan="5" rowspan="2"></td><td colspan="3" rowspan="3">5 × USARTs
4 × 16-bit timers,
2 × basic timers, 3 × SPIs,
2 × I²Ss, 2 × I2Cs, USB,
CAN, 2 × PWM timers
3 × ADCs, 2 × DACs,
1 × SDIO, FSMC (100- and 144-pin packages(2))</td><td colspan="5"></td></tr>
<tr><td>100 pins</td><td colspan="3" rowspan="2">3 × USARTs
3 × 16-bit timers
2 × SPIs,
2 × I²Cs, USB, CAN,
1 × PWM timer
2 × ADCs</td><td colspan="3" rowspan="2">5 × USARTs,
4 × 16-bit timers,
2 × basic timers,
3 × SPIs,
2 × I²Ss,
2 × I2Cs,
USB OTG FS,
2 × CANs,
1 × PWM timer,
2 × ADCs,
2 × DACs</td><td colspan="2" rowspan="2">5 × USARTs,
4 × 16-bit timers,
2 × basic timers,
3 × SPIs,
2 × I²S,
1 × I2C,
USB OTG FS,
2 × CANs,
1 × PWM timer,
2 × ADCs,
2 × DACs,
Ethernet</td></tr>
<tr><td>64 pins</td><td colspan="2" rowspan="3">2 × USARTs
2 × 16-bit timers
1 × SPI, 1 × I²C, USB, CAN,
1 × PWM timer
2 × ADCs</td><td colspan="2" rowspan="3">2 × USARTs
2 × 16-bit timers
1 × SPI,
1 × I²C,
USB, CAN,
1 × PWM timer
2 × ADCs</td></tr>
<tr><td>48 pins</td><td colspan="3"></td></tr>
<tr><td>36 pins</td><td colspan="3"></td></tr>
</table>

1. Refer to *Table 5: Pin definitions* for peripheral availability when the I/O pins are shared by the peripherals required by the application.
2. Ports F and G are not available in devices delivered in 100-pin packages.

2.3 Overview

Figure 1. STM32F105xx and STM32F107xx connectivity line block diagram



1. T_A = –40 °C to +85 °C (suffix 6, see *Table 62*) or –40 °C to +105 °C (suffix 7, see *Table 62*), junction temperature up to 105 °C or 125 °C, respectively.
2. AF = alternate function on I/O port pin.

2.3.15 Timers and watchdogs

The STM32F105xx and STM32F107xx devices include an advanced-control timer, four general-purpose timers, two basic timers, two watchdog timers and a SysTick timer.

Table 4 compares the features of the general-purpose and basic timers.

Table 4. Timer feature comparison

Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary outputs
TIM1	16-bit	Up, down, up/down	Any integer between 1 and 65536	Yes	4	Yes
TIMx (TIM2, TIM3, TIM4, TIM5)	16-bit	Up, down, up/down	Any integer between 1 and 65536	Yes	4	No
TIM6, TIM7	16-bit	Up	Any integer between 1 and 65536	Yes	0	No

Advanced-control timer (TIM1)

The advanced control timer (TIM1) can be seen as a three-phase PWM multiplexed on 6 channels. It has complementary PWM outputs with programmable inserted dead-times. It can also be seen as a complete general-purpose timer. The 4 independent channels can be used for:

- Input capture
- Output compare
- PWM generation (edge or center-aligned modes)
- One-pulse mode output

If configured as a standard 16-bit timer, it has the same features as the TIMx timer. If configured as the 16-bit PWM generator, it has full modulation capability (0-100%).

The counter can be frozen in debug mode.

Many features are shared with those of the standard TIM timers which have the same architecture. The advanced control timer can therefore work together with the TIM timers via the Timer Link feature for synchronization or event chaining.

General-purpose timers (TIMx)

There are up to 4 synchronizable standard timers (TIM2, TIM3, TIM4 and TIM5) embedded in the STM32F105xx and STM32F107xx connectivity line devices. These timers are based on a 16-bit auto-reload up/down counter, a 16-bit prescaler and feature 4 independent channels each for input capture/output compare, PWM or one pulse mode output. This gives up to 16 input captures / output compares / PWMs on the largest packages. They can work together with the Advanced Control timer via the Timer Link feature for synchronization or event chaining.

The counter can be frozen in debug mode.

Table 5. Pin definitions (continued)

Pins			Pin name	Type[1]	I / O Level[2]	Main function[3] (after reset)	Alternate functions[4]	
BGA100	LQFP64	LQFP100					Default	Remap
J9	-	56	PD9	I/O	FT	PD9	-	USART3_RX/ ETH_MII_RXD0/ ETH_RMII_RXD0
H9	-	57	PD10	I/O	FT	PD10	-	USART3_CK/ ETH_MII_RXD1/ ETH_RMII_RXD1
G9	-	58	PD11	I/O	FT	PD11	-	USART3_CTS/ ETH_MII_RXD2
K10	-	59	PD12	I/O	FT	PD12	-	TIM4_CH1 / USART3_RTS/ ETH_MII_RXD3
J10	-	60	PD13	I/O	FT	PD13	-	TIM4_CH2
H10	-	61	PD14	I/O	FT	PD14	-	TIM4_CH3
G10	-	62	PD15	I/O	FT	PD15	-	TIM4_CH4
F10	37	63	PC6	I/O	FT	PC6	I2S2_MCK/	TIM3_CH1
E10	38	64	PC7	I/O	FT	PC7	I2S3_MCK	TIM3_CH2
F9	39	65	PC8	I/O	FT	PC8	-	TIM3_CH3
E9	40	66	PC9	I/O	FT	PC9	-	TIM3_CH4
D9	41	67	PA8	I/O	FT	PA8	USART1_CK/OTG_FS_SOF / TIM1_CH1[8]/MCO	-
C9	42	68	PA9	I/O	FT	PA9	USART1_TX[7]/ TIM1_CH2[7]/ OTG_FS_VBUS	-
D10	43	69	PA10	I/O	FT	PA10	USART1_RX[7]/ TIM1_CH3[7]/OTG_FS_ID	-
C10	44	70	PA11	I/O	FT	PA11	USART1_CTS / CAN1_RX / TIM1_CH4[7]/OTG_FS_DM	-
B10	45	71	PA12	I/O	FT	PA12	USART1_RTS / OTG_FS_DP / CAN1_TX[7] / TIM1_ETR[7]	-
A10	46	72	PA13	I/O	FT	JTMS-SWDIO	-	PA13
F8	-	73	Not connected					-
E6	47	74	V_{SS_2}	S	-	V_{SS_2}	-	-
F6	48	75	V_{DD_2}	S	-	V_{DD_2}	-	-
A9	49	76	PA14	I/O	FT	JTCK-SWCLK	-	PA14

Table 8. Thermal characteristics

Symbol	Ratings	Value	Unit
T_{STG}	Storage temperature range	–65 to +150	°C
T_J	Maximum junction temperature	150	°C

5.3 Operating conditions

5.3.1 General operating conditions

Table 9. General operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
f_{HCLK}	Internal AHB clock frequency	-	0	72	MHz
f_{PCLK1}	Internal APB1 clock frequency	-	0	36	
f_{PCLK2}	Internal APB2 clock frequency	-	0	72	
V_{DD}	Standard operating voltage	-	2	3.6	V
V_{DDA}(1)	Analog operating voltage (ADC not used)	Must be the same potential as V_{DD}(2)	2	3.6	V
	Analog operating voltage (ADC used)		2.4	3.6	
V_{BAT}	Backup operating voltage	-	1.8	3.6	V
P_D	Power dissipation at T_A = 85 °C for suffix 6 or T_A = 105 °C for suffix 7(3)	LFBGA100	-	500	mW
		LQFP100	-	434	
		LQFP64	-	444	
P_D	Power dissipation at T_A = 85 °C for suffix 6 or T_A = 105 °C for suffix 7(4)	LQFP100	-	434	mW
		LQFP64	-	444	
T_A	Ambient temperature for 6 suffix version	Maximum power dissipation	–40	85	°C
		Low power dissipation(5)	–40	105	
	Ambient temperature for 7 suffix version	Maximum power dissipation	–40	105	°C
		Low power dissipation(5)	–40	125	
T_J	Junction temperature range	6 suffix version	–40	105	°C
		7 suffix version	–40	125	

1. When the ADC is used, refer to *Table 52: ADC characteristics*.
2. It is recommended to power V_{DD} and V_{DDA} from the same source. A maximum difference of 300 mV between V_{DD} and V_{DDA} can be tolerated during power-up and operation.
3. If T_A is lower, higher P_D values are allowed as long as T_J does not exceed $T_J$max.
4. If T_A is lower, higher P_D values are allowed as long as T_J does not exceed $T_J$max.
5. In low power dissipation state, T_A can be extended to this range as long as T_J does not exceed $T_J$max.

Table 17. Typical current consumption in Run mode, code with data processing running from Flash

Symbol	Parameter	Conditions	f_{HCLK}	Typ(1)		Unit
				All peripherals enabled(2)	All peripherals disabled	
I_{DD}	Supply current in Run mode	External clock(3)	72 MHz	47.3	28.3	mA
			48 MHz	32	19.6	
			36 MHz	24.6	15.4	
			24 MHz	16.8	10.6	
			16 MHz	11.8	7.4	
			8 MHz	5.9	3.7	
			4 MHz	3.7	2.9	
			2 MHz	2.5	2	
			1 MHz	1.8	1.53	
			500 kHz	1.5	1.3	
			125 kHz	1.3	1.2	
		Running on high speed internal RC (HSI), AHB prescaler used to reduce the frequency	36 MHz	23.9	14.8	mA
			24 MHz	16.1	9.7	
			16 MHz	11.1	6.7	
			8 MHz	5.6	3.8	
			4 MHz	3.1	2.1	
			2 MHz	1.8	1.3	
			1 MHz	1.16	0.9	
			500 kHz	0.8	0.67	
			125 kHz	0.6	0.5	

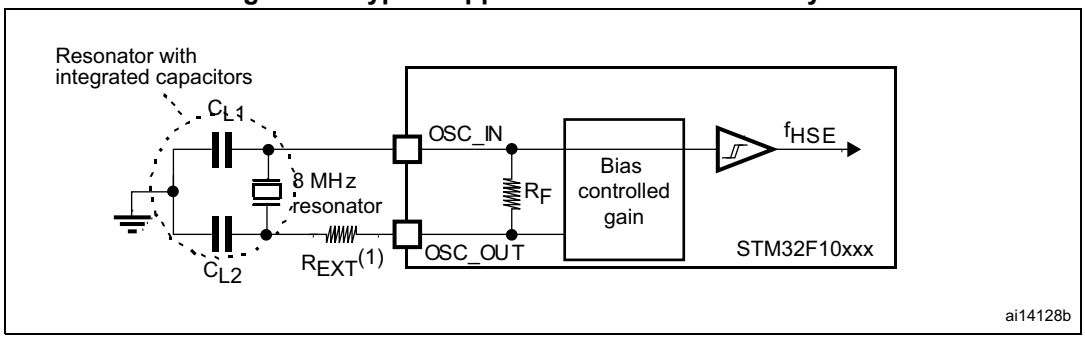
1. Typical values are measures at T_A = 25 °C, V_{DD} = 3.3 V.
2. Add an additional power consumption of 0.8 mA per ADC for the analog part. In applications, this consumption occurs only while the ADC is on (ADON bit is set in the ADC_CR2 register).
3. External clock is 8 MHz and PLL is on when f_{HCLK} > 8 MHz.

Table 19. Peripheral current consumption

Peripheral		Typical consumption at 25 °C	Unit
AHB (up to 72 MHz)	DMA1	14.03	µA/MHz
	DMA2	9.31	
	OTG_fs	111.11	
	ETH-MAC	56.25	
	CRC	1.11	
	BusMatrix(1)	15.97	
APB1(up to 36MHz)	APB1-Bridge	9.72	µA/MHz
	TIM2	33.61	
	TIM3	33.06	
	TIM4	32.50	
	TIM5	31.94	
	TIM6	6.11	
	TIM7	6.11	
	SPI2/I2S2(2)	7.50	
	SPI3/I2S3(2)	7.50	
	USART2	10.83	
	USART3	11.11	
	UART4	10.83	
	UART5	10.56	
	I2C1	11.39	
	I2C2	11.11	
	CAN1	19.44	
	CAN2	18.33	
	DAC(3)	8.61	
	WWDG	3.33	
	PWR	2.22	
	BKP	0.83	
	IWDG	3.89	

For C_{L1} and C_{L2}, it is recommended to use high-quality external ceramic capacitors in the 5 pF to 25 pF range (typ.), designed for high-frequency applications, and selected to match the requirements of the crystal or resonator (see *Figure 16*). C_{L1} and C_{L2} are usually the same size. The crystal manufacturer typically specifies a load capacitance which is the series combination of C_{L1} and C_{L2}. PCB and MCU pin capacitance must be included (10 pF can be used as a rough estimate of the combined pin and board capacitance) when sizing C_{L1} and C_{L2}. Refer to the application note AN2867 “Oscillator design guide for ST microcontrollers” available from the ST website *www.st.com*.

Figure 16. Typical application with an 8 MHz crystal



1. R_{EXT} value depends on the crystal characteristics.

Low-speed external clock generated from a crystal/ceramic resonator

The low-speed external (LSE) clock can be supplied with a 32.768 kHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on characterization results obtained with typical external components specified in *Table 23*. In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

Table 23. LSE oscillator characteristics (f_{LSE} = 32.768 kHz) (1)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
R_F	Feedback resistor	-	-	5	-	MΩ
$C^{(2)}$	Recommended load capacitance versus equivalent serial resistance of the crystal (R_S)(3)	R_S = 30 kΩ	-	-	15	pF
I_2	LSE driving current	V_{DD} = 3.3 V, V_{IN} = V_{SS}	-	-	1.4	µA
g_m	Oscillator Transconductance	-	5	-	-	µA/V

5.3.7 Internal clock source characteristics

The parameters given in *Table 24* are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in *Table 9*.

High-speed internal (HSI) RC oscillator

Table 24. HSI oscillator characteristics (1)

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
f_{HSI}	Frequency	-		-	8		MHz
$DuCy_{(HSI)}$	Duty cycle	-		45	-	55	%
ACC_{HSI}	Accuracy of the HSI oscillator	User-trimmed with the RCC_CR register(2)		-	-	1(3)	%
		Factory-calibrated(4)	T_A = –40 to 105 °C	–2	-	2.5	%
			T_A = –10 to 85 °C	–1.5	-	2.2	%
			T_A = 0 to 70 °C	–1.3	-	2	%
			T_A = 25 °C	–1.1	-	1.8	%
$t_{su(HSI)}$(4)	HSI oscillator startup time	-		1	-	2	µs
$I_{DD(HSI)}$(4)	HSI oscillator power consumption	-		-	80	100	µA

1. V_{DD} = 3.3 V, T_A = –40 to 105 °C unless otherwise specified.
2. Refer to application note AN2868 “STM32F10xxx internal RC oscillator (HSI) calibration” available from the ST website *www.st.com*.
3. Guaranteed by design, not tested in production.
4. Based on characterization, not tested in production.

Low-speed internal (LSI) RC oscillator

Table 25. LSI oscillator characteristics (1)

Symbol	Parameter	Min	Typ	Max	Unit
f_{LSI}(2)	Frequency	30	40	60	kHz
$t_{su(LSI)}$(3)	LSI oscillator startup time	-	-	85	µs
$I_{DD(LSI)}$(3)	LSI oscillator power consumption	-	0.65	1.2	µA

1. V_{DD} = 3 V, T_A = –40 to 105 °C unless otherwise specified.
2. Based on characterization, not tested in production.
3. Guaranteed by design, not tested in production.

Wakeup time from low-power mode

The wakeup times given in *Table 26* is measured on a wakeup phase with a 8-MHz HSI RC oscillator. The clock source used to wake up the device depends from the current operating mode:

- Stop or Standby mode: the clock source is the RC oscillator
- Sleep mode: the clock source is the clock that was set before entering Sleep mode.

Table 32. EMI characteristics

Symbol	Parameter	Conditions	Monitored frequency band	Max vs. [f_{HSE}/f_{HCLK}]		Unit
				8/48 MHz	8/72 MHz	
S_{EMI}	Peak level	V_{DD} = 3.3 V, T_A = 25 °C, LQFP100 package compliant with IEC61967-2	0.1 to 30 MHz	9	9	dBµV
			30 to 130 MHz	26	13	
			130 MHz to 1GHz	25	31	
			EMI Level	4	4	-

5.3.11 Absolute maximum ratings (electrical sensitivity)

Based on three different tests (ESD, LU) using specific measurement methods, the device is stressed in order to determine its performance in terms of electrical sensitivity.

Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse separated by 1 second) are applied to the pins of each sample according to each pin combination. The sample size depends on the number of supply pins in the device (3 parts × (n+1) supply pins). This test conforms to the JESD22-A114/C101 standard.

Table 33. ESD absolute maximum ratings

Symbol	Ratings	Conditions	Class	Maximum value(1)	Unit
$V_{ESD(HBM)}$	Electrostatic discharge voltage (human body model)	T_A = +25 °C conforming to JESD22-A114	2	2000	V
$V_{ESD(CDM)}$	Electrostatic discharge voltage (charge device model)	T_A = +25 °C conforming to JESD22-C101	II	500	

1. Based on characterization results, not tested in production.

Static latch-up

Two complementary static tests are required on six parts to assess the latch-up performance:

- A supply overvoltage is applied to each power supply pin
- A current injection is applied to each input, output and configurable I/O pin

These tests are compliant with EIA/JESD 78A IC latch-up standard.

Table 34. Electrical sensitivities

Symbol	Parameter	Conditions	Class
LU	Static latch-up class	T_A = +105 °C conforming to JESD78A	II level A

5.3.12 I/O current injection characteristics

As a general rule, current injection to the I/O pins, due to external voltage below V_{SS} or above V_{DD} (for standard, 3 V-capable I/O pins) should be avoided during normal product

Output driving current

The GPIOs (general purpose input/outputs) can sink or source up to +/-8 mA, and sink or source up to +/-20 mA (with a relaxed V_{OL}/V_{OH}).

In the user application, the number of I/O pins which can drive current must be limited to respect the absolute maximum rating specified in *Section 5.2*:

- The sum of the currents sourced by all the I/Os on $V_{DD,}$ plus the maximum Run consumption of the MCU sourced on $V_{DD,}$ cannot exceed the absolute maximum rating I_{VDD} (see *Table 7*).
- The sum of the currents sunk by all the I/Os on V_{SS} plus the maximum Run consumption of the MCU sunk on V_{SS} cannot exceed the absolute maximum rating I_{VSS} (see *Table 7*).

Output voltage levels

Unless otherwise specified, the parameters given in *Table 37* are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in *Table 9*. All I/Os are CMOS and TTL compliant.

Table 37. Output voltage characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
V_{OL}(1)	Output low level voltage for an I/O pin when 8 pins are sunk at same time	TTL port I_{IO} = +8 mA 2.7 V < V_{DD} < 3.6 V	-	0.4	V
V_{OH}(2)	Output high level voltage for an I/O pin when 8 pins are sourced at same time		V_{DD}–0.4	-	
V_{OL} (1)	Output low level voltage for an I/O pin when 8 pins are sunk at same time	CMOS port I_{IO} =+ 8mA 2.7 V < V_{DD} < 3.6 V	-	0.4	V
V_{OH} (2)	Output high level voltage for an I/O pin when 8 pins are sourced at same time		2.4	-	
V_{OL}(1)(3)	Output low level voltage for an I/O pin when 8 pins are sunk at same time	I_{IO} = +20 mA 2.7 V < V_{DD} < 3.6 V	-	1.3	V
V_{OH}(2)(3)	Output high level voltage for an I/O pin when 8 pins are sourced at same time		V_{DD}–1.3	-	
V_{OL}(1)(3)	Output low level voltage for an I/O pin when 8 pins are sunk at same time	I_{IO} = +6 mA 2 V < V_{DD} < 2.7 V	-	0.4	V
V_{OH}(2)(3)	Output high level voltage for an I/O pin when 8 pins are sourced at same time		V_{DD}–0.4	-	

1. The I_{IO} current sunk by the device must always respect the absolute maximum rating specified in *Table 7* and the sum of I_{IO} (I/O ports and control pins) must not exceed I_{VSS}.
2. The I_{IO} current sourced by the device must always respect the absolute maximum rating specified in *Table 7* and the sum of I_{IO} (I/O ports and control pins) must not exceed I_{VDD}.
3. Based on characterization data, not tested in production.

Input/output AC characteristics

The definition and values of input/output AC characteristics are given in *Figure 22* and *Table 38*, respectively.

Unless otherwise specified, the parameters given in *Table 38* are derived from tests performed under the ambient temperature and V_{DD} supply voltage conditions summarized in *Table 9*.

Table 38. I/O AC characteristics(1)

MODEx[1:0] bit value(1)	Symbol	Parameter	Conditions	Min	Max	Unit
10	$f_{max(IO)out}$	Maximum frequency(2)	C_L = 50 pF, V_{DD} = 2 V to 3.6 V	-	2	MHz
	$t_{f(IO)out}$	Output high to low level fall time	C_L = 50 pF, V_{DD} = 2 V to 3.6 V	-	125(3)	ns
	$t_{r(IO)out}$	Output low to high level rise time		-	125(3)	
01	$f_{max(IO)out}$	Maximum frequency(2)	C_L = 50 pF, V_{DD} = 2 V to 3.6 V	-	10	MHz
	$t_{f(IO)out}$	Output high to low level fall time	C_L = 50 pF, V_{DD} = 2 V to 3.6 V	-	25(3)	ns
	$t_{r(IO)out}$	Output low to high level rise time		-	25(3)	
11	$F_{max(IO)out}$	Maximum frequency(2)	C_L = 30 pF, V_{DD} = 2.7 V to 3.6 V	-	50	MHz
			C_L = 50 pF, V_{DD} = 2.7 V to 3.6 V	-	30	MHz
			C_L = 50 pF, V_{DD} = 2 V to 2.7 V	-	20	MHz
	$t_{f(IO)out}$	Output high to low level fall time	C_L = 30 pF, V_{DD} = 2.7 V to 3.6 V	-	5(3)	ns
			C_L = 50 pF, V_{DD} = 2.7 V to 3.6 V	-	8(3)	
			C_L = 50 pF, V_{DD} = 2 V to 2.7 V	-	12(3)	
	$t_{r(IO)out}$	Output low to high level rise time	C_L = 30 pF, V_{DD} = 2.7 V to 3.6 V	-	5(3)	
			C_L = 50 pF, V_{DD} = 2.7 V to 3.6 V	-	8(3)	
			C_L = 50 pF, V_{DD} = 2 V to 2.7 V	-	12(3)	
-	t_{EXTIpw}	Pulse width of external signals detected by the EXTI controller	-	10	-	ns

1. The I/O speed is configured using the MODEx[1:0] bits. Refer to the STM32F10xxx reference manual for a description of GPIO Port configuration register.
2. The maximum frequency is defined in *Figure 22*.
3. Guaranteed by design, not tested in production.

Table 51. Dynamic characteristics: Ethernet MAC signals for MII

Symbol	Rating	Min	Typ	Max	Unit
$t_{su(RXD)}$	Receive data setup time	10	-	-	ns
$t_{ih(RXD)}$	Receive data hold time	10	-	-	ns
$t_{su(DV)}$	Data valid setup time	10	-	-	ns
$t_{ih(DV)}$	Data valid hold time	10	-	-	ns
$t_{su(ER)}$	Error setup time	10	-	-	ns
$t_{ih(ER)}$	Error hold time	10	-	-	ns
$t_{d(TXEN)}$	Transmit enable valid delay time	14	16	18	ns
$t_{d(TXD)}$	Transmit data valid delay time	13	16	20	ns

CAN (controller area network) interface

Refer to *Section 5.3.12: I/O current injection characteristics* for more details on the input/output alternate function characteristics (CANTX and CANRX).

5.3.17 12-bit ADC characteristics

Unless otherwise specified, the parameters given in *Table 52* are derived from tests performed under the ambient temperature, f_{PCLK2} frequency and V_{DDA} supply voltage conditions summarized in *Table 9*.

Note: It is recommended to perform a calibration after each power-up.

Table 52. ADC characteristics

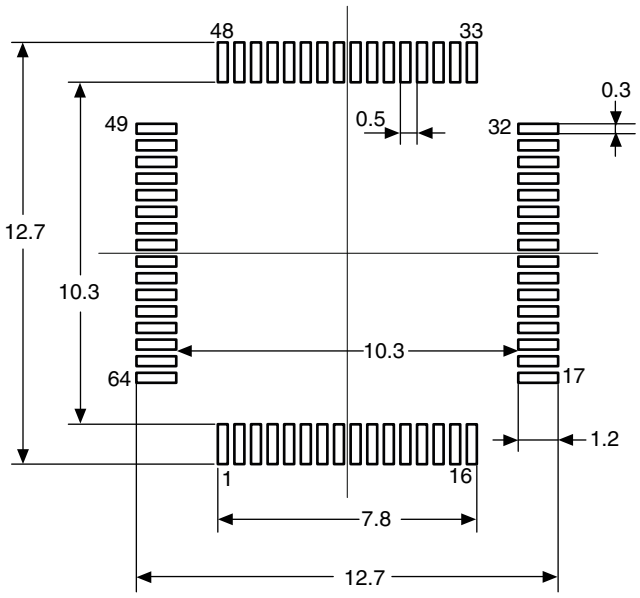
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{DDA}	Power supply	-	2.4	-	3.6	V
V_{REF+}	Positive reference voltage	-	2.4	-	V_{DDA}	V
I_{VREF}	Current on the V_{REF} input pin	-	-	160(1)	220(1)	µA
f_{ADC}	ADC clock frequency	-	0.6	-	14	MHz
f_S(2)	Sampling rate	-	0.05	-	1	MHz
f_{TRIG}(2)	External trigger frequency	f_{ADC} = 14 MHz	-	-	823	kHz
		-	-	-	17	$1/f_{ADC}$
V_{AIN}	Conversion voltage range(3)	-	0 (V_{SSA} or V_{REF-} tied to ground)	-	V_{REF+}	V
R_{AIN}(2)	External input impedance	See *Equation 1* and *Table 53* for details	-	-	50	kΩ
R_{ADC}(2)	Sampling switch resistance	-	-	-	1	kΩ
C_{ADC}(2)	Internal sample and hold capacitor	-	-	-	8	pF
t_{CAL}(2)	Calibration time	f_{ADC} = 14 MHz	5.9			µs
		-	83			$1/f_{ADC}$

Table 60.LQFP64 – 10 x 10 mm 64 pin low-profile quad flat package mechanical data

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
e	-	0.500	-	-	0.0197	-
θ	0°	3.5°	7°	0°	3.5°	7°
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

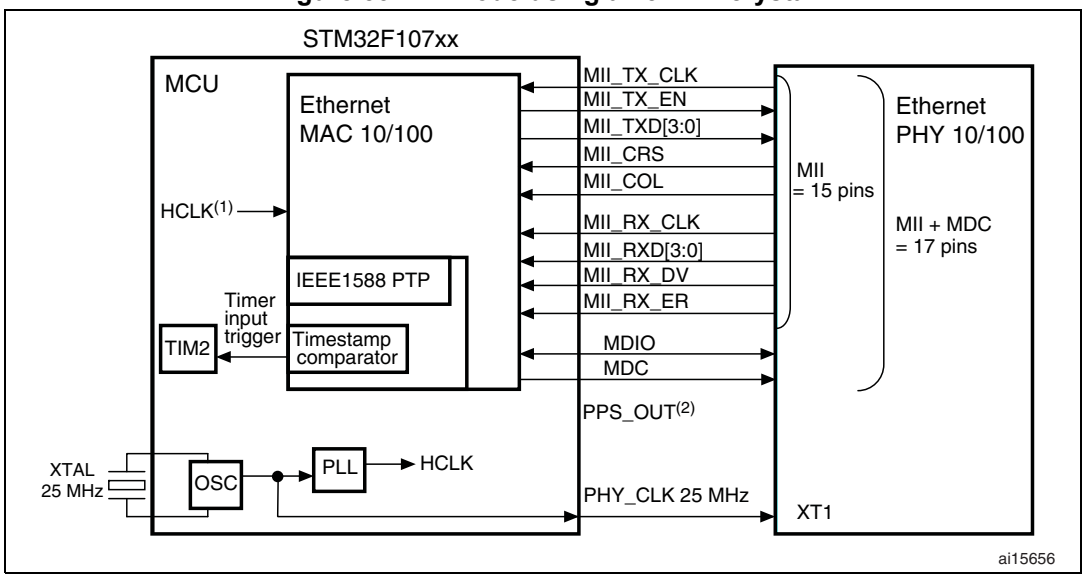
Figure 47.LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat recommended footprint



1. Dimensions are in millimeters.

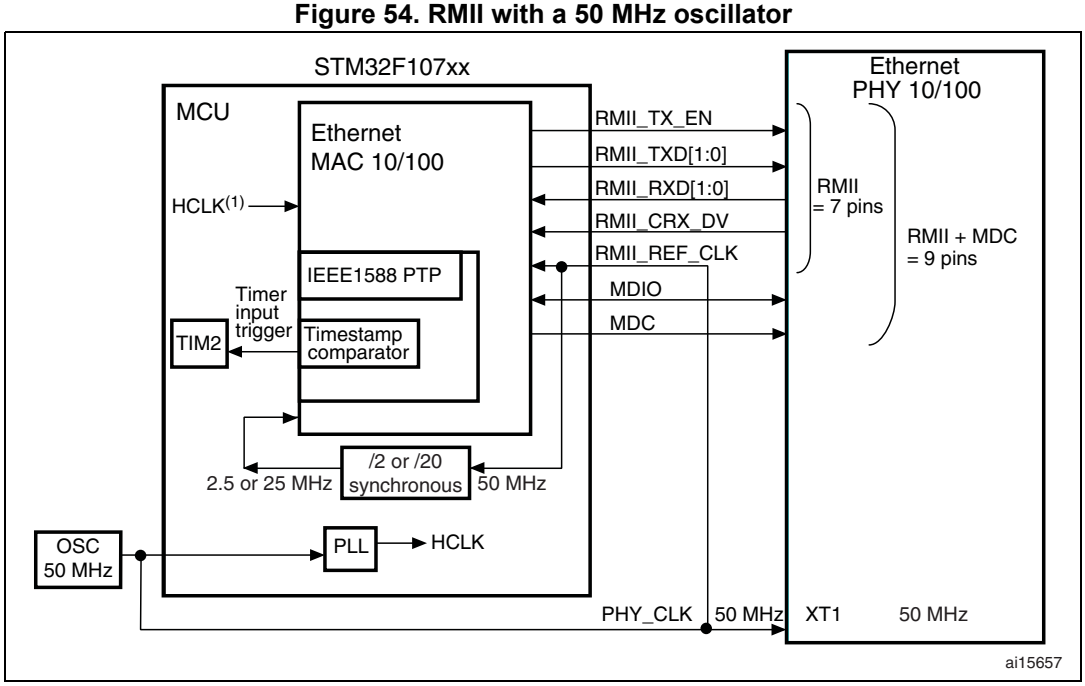
A.2 Ethernet interface solutions

Figure 53. MII mode using a 25 MHz crystal



1. HCLK must be greater than 25 MHz.
2. Pulse per second when using IEEE1588 PTP, optional signal.

Figure 54. RMII with a 50 MHz oscillator



1. HCLK must be greater than 25 MHz.

A.3 Complete audio player solutions

Two solutions are offered, illustrated in *Figure 57* and *Figure 58*.

Figure 57 shows storage media to audio DAC/amplifier streaming using a software Codec. This solution implements an audio crystal to provide audio class I^2S accuracy on the master clock (0.5% error maximum, see the Serial peripheral interface section in the reference manual for details).

Figure 57. Complete audio player solution 1

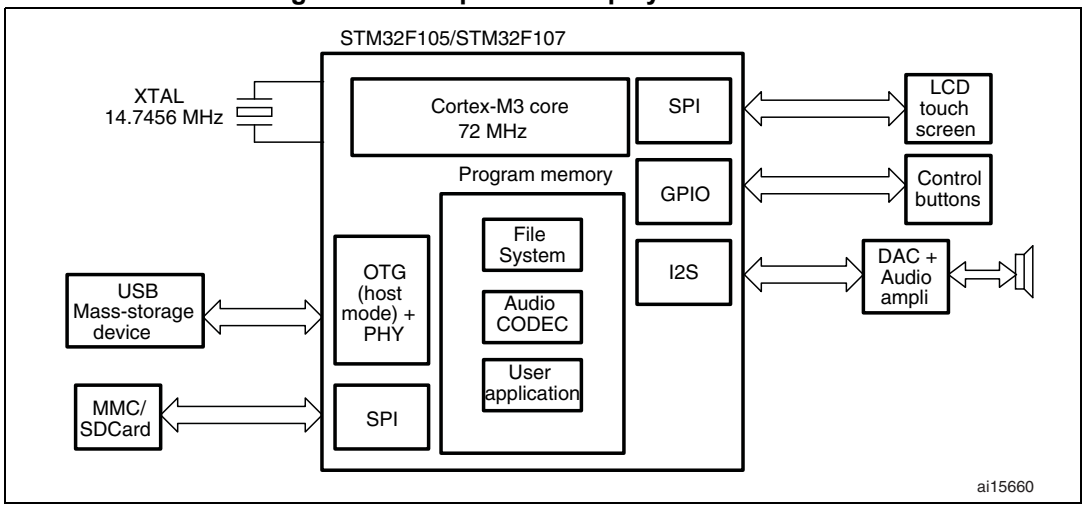


Figure 58 shows storage media to audio Codec/amplifier streaming with SOF synchronization of input/output audio streaming using a hardware Codec.

Figure 58. Complete audio player solution 2

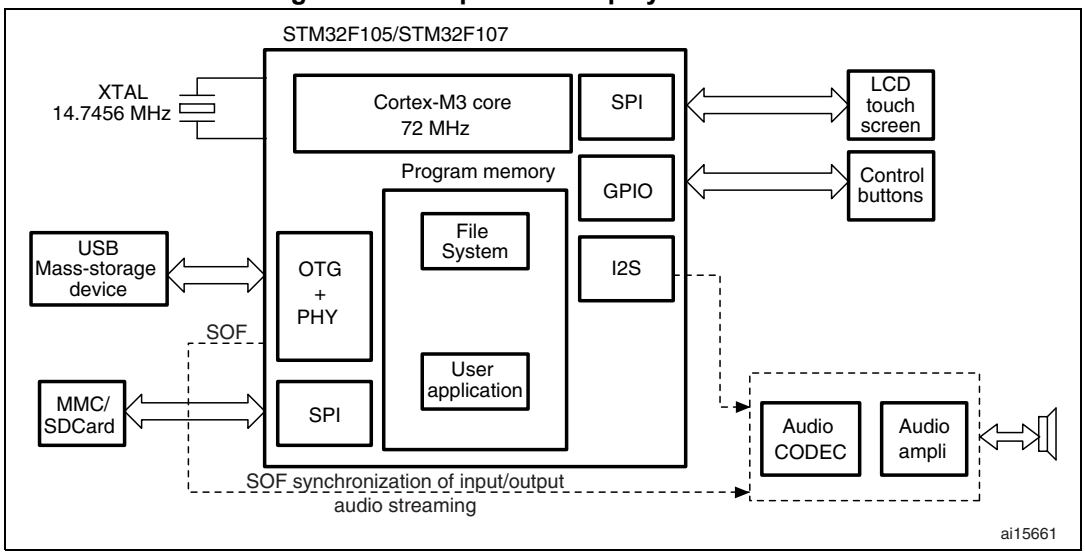


Table 64. Applicative current consumption in Run mode, code with data processing running from Flash

Symbol	parameter	Conditions[1]	Typ[2]	Max[2]		Unit
				85 °C	105 °C	
I_{DD}	Supply current in run mode	External clock, all peripherals enabled except ethernet, HSE = 8 MHz, f_{HCLK} = 72 MHz, no MCO	57	63	64	mA
		External clock, all peripherals enabled except ethernet, HSE = 14.74 MHz, f_{HCLK} = 72 MHz, no MCO	60.5	67	68	
		External clock, all peripherals enabled except OTG, HSE = 25 MHz, f_{HCLK} = 72 MHz, MCO = 25 MHz	53	60.7	61	
		External clock, all peripherals enabled, HSE = 25 MHz, f_{HCLK} = 72 MHz, MCO = 25 MHz	60.5	65.5	66	
		External clock, all peripherals enabled, HSE = 25 MHz, f_{HCLK} = 72 MHz, MCO = 50 MHz	64	69.7	70	
		External clock, all peripherals enabled, HSE = 50 MHz[3], f_{HCLK} = 72 MHz, no MCO	62.5	67.5	68	
		External clock, only OTG enabled, HSE = 8 MHz, f_{HCLK} = 48 MHz, no MCO	26.7	None	None	
		External clock, only ethernet enabled, HSE = 25 MHz, f_{HCLK} = 25 MHz, MCO = 25 MHz	14.3	None	None	

1. V_{DD} = 3.3 V.
2. Based on characterization, not tested in production.
3. External oscillator.

8 Revision history

Table 65. Document revision history

Date	Revision	Changes
18-Dec-2008	1	Initial release.
20-Feb-2009	2	I/O information clarified *on page 1. Figure 4: STM32F105xxx and STM32F107xxx connectivity line BGA100 ballout top view* corrected. *Section 2.3.8: Boot modes* updated. PB4, PB13, PB14, PB15, PB3/TRACESWO moved from Default column to Remap column, plus small additional changes in *Table 5: Pin definitions*. Consumption values modified in *Section 5.3.5: Supply current characteristics*. Note modified in *Table 13: Maximum current consumption in Run mode, code with data processing running from Flash* and *Table 15: Maximum current consumption in Sleep mode, code running from Flash or RAM*. *Table 20: High-speed external user clock characteristics* and *Table 21: Low-speed external user clock characteristics* modified. *Table 27: PLL characteristics* modified and *Table 28: PLL2 and PLL3 characteristics* added.